HALOGEN FREE



Vishay Siliconix

N-Channel 30-V (D-S) MOSFET

PRODUCT SUMMARY					
V _{DS} (V)	$R_{DS(on)}\left(\Omega\right)$	I _D (A) ^a	Q _g (Typ.)		
30	0.024 at V _{GS} = 10 V	10.9	3.8 nC		
	0.030 at V _{GS} = 4.5 V	9.7	3.0 110		

		SO-8		
S 2 S 3 G 4	=		8 7 6 5	D D D
		Top View		

Ordering Information: Si4128DY-T1-E3 (Lead (Pb)-free)

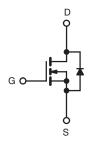
Si4128DY-T1-GE3 (Lead (Pb)-free and Halogen-free)

FEATURES

- Halogen-free According to IEC 61249-2-21 Available
- TrenchFET® Power MOSFET
- 100 % R_g Tested

APPLICATIONS

- Notebook PC
 - System Power
 - Load Switch



N-Channel MOSFET

ABSOLUTE MAXIMUM RATIN	I GS T _A = 25 °C,	unless other	wise noted		
Parameter	Symbol	Limit	Unit		
Drain-Source Voltage	V_{DS}	30	V		
Gate-Source Voltage		V_{GS}	± 20	V	
	T _C = 25 °C		10.9		
Continuous Drain Current (T _{.1} = 150 °C)	T _C = 70 °C	i .	8.7		
Continuous Diam Current (1, = 150 °C)	T _A = 25 °C	l o	7.5 ^{b, c}		
	T _A = 70 °C	1 -	6 ^{b, c}	Α	
Pulsed Drain Current		I _{DM}	30		
Continuous Source-Drain Diode Current	T _C = 25 °C	l-	4.2		
	T _A = 25 °C	l _S	2 ^{b, c}		
Maximum Power Dissipation	T _C = 25 °C		5		
	T _C = 70 °C	P _D	3.2	w	
	T _A = 25 °C		2.4 ^{b, c}	VV	
	T _A = 70 °C	1	1.5 ^{b, c}		
Operating Junction and Storage Temperature Range		T _J , T _{sta}	- 55 to 150	°C	

THERMAL RESISTANCE RATINGS						
Parameter	Symbol	Typical	Maximum	Unit		
Maximum Junction-to-Ambient ^{b, d}	t ≤ 10 s	R_{thJA}	42	53	°C/W	
Maximum Junction-to-Foot (Drain)	Steady State	R_{thJF}	19	25	J 5/ VV	

Notes:

- a. $T_C = 25$ °C.
- b. Surface Mounted on 1" x 1" FR4 board.
- c. t = 10 s
- d. Maximum under Steady State conditions is 85 $^{\circ}$ C/W.

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Parameter	Symbol	Test Conditions	Min.	Тур.	Max.	Unit	
Static	-			, ,,			
Drain-Source Breakdown Voltage	V _{DS}	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$	30			V	
V _{DS} Temperature Coefficient	ΔV _{DS} /T _J	L 050 ·· A		35		mV/°C	
V _{GS(th)} Temperature Coefficient	$\Delta V_{GS(th)}/T_J$	I _D = 250 μA		- 4.5			
Gate-Source Threshold Voltage	V _{GS(th)}	$V_{DS} = V_{GS}$, $I_D = 250 \mu A$	1.0		2.5	V	
Gate-Source Leakage	I _{GSS}	$V_{DS} = 0 \text{ V}, V_{GS} = \pm 20 \text{ V}$			± 100	nA	
Zero Gate Voltage Drain Current	1	$V_{DS} = 30 \text{ V}, V_{GS} = 0 \text{ V}$			1	μΑ	
	I _{DSS}	V _{DS} = 30 V, V _{GS} = 0 V, T _J = 55 °C			5		
On-State Drain Current ^a	I _{D(on)}	$V_{DS} \ge 5 \text{ V}, V_{GS} = 10 \text{ V}$	20			Α	
_	5	$V_{GS} = 10 \text{ V}, I_D = 7.8 \text{ A}$		0.020	0.024	Ω	
Drain-Source On-State Resistance ^a	R _{DS(on)}	$V_{GS} = 4.5 \text{ V}, I_D = 7.0 \text{ A}$		0.024	0.030		
Forward Transconductance ^a	9 _{fs}	$V_{DS} = 10 \text{ V}, I_D = 7.8 \text{ A}$		17		S	
Dynamic ^b						1	
Input Capacitance	C _{iss}			435			
Output Capacitance	C _{oss}	$V_{DS} = 15 \text{ V}, V_{GS} = 0 \text{ V}, f = 1 \text{ MHz}$		95		pF	
Reverse Transfer Capacitance	C _{rss}			42			
Total Gate Charge	Q_g	$V_{DS} = 15 \text{ V}, V_{GS} = 10 \text{ V}, I_D = 7.8 \text{ A}$		8	12	nC	
				3.8	6		
Gate-Source Charge	Q_{gs}	$V_{DS} = 15 \text{ V}, V_{GS} = 4.5 \text{ V}, I_{D} = 7.8 \text{ A}$		1.4			
Gate-Drain Charge	Q_{gd}			1.1			
Gate Resistance	R_{g}	f = 1 MHz	1.5	3.2	4.5	Ω	
Turn-On Delay Time	t _{d(on)}			15	25	ns	
Rise Time	t _r	V_{DD} = 15 V, R_L = 2.4 Ω		12	20		
Turn-Off Delay Time	t _{d(off)}	$I_D\cong 6.3$ A, $V_{GEN}=4.5$ V, $R_g=1$ Ω		13	20		
Fall Time	t _f			10	15		
Turn-On Delay Time	t _{d(on)}			5	10		
Rise Time	t _r	V_{DD} = 15 V, R_L = 2.4 Ω		10	15		
Turn-Off Delay Time	t _{d(off)}	$I_D\cong 6.3$ A, V_{GEN} = 10 V, R_g = 1 Ω		15	25		
Fall Time	t _f			10	15		
Drain-Source Body Diode Characteristi	cs						
Continuous Source-Drain Diode Current	I _S	T _C = 25 °C			4.2	٨	
Pulse Diode Forward Current	I _{SM}				30	Α	
Body Diode Voltage	V_{SD}	$I_S = 6.3 \text{ A}, V_{GS} = 0 \text{ V}$		0.8	1.2	V	
Body Diode Reverse Recovery Time	t _{rr}			15	25	ns	
Body Diode Reverse Recovery Charge	Q _{rr}	L_ = 6.3 A dl/dt = 100 A/vo T = 25.00		7	12	nC	
Reverse Recovery Fall Time	ta	$I_F = 6.3 \text{ A}, \text{ dI/dt} = 100 \text{ A/}\mu\text{s}, T_J = 25 ^{\circ}\text{C}$		9		1	
Reverse Recovery Rise Time				6		ns	

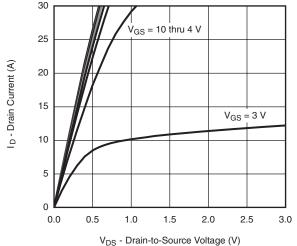
- a. Pulse test; pulse width \leq 300 $\mu s,$ duty cycle \leq 2 %
- b. Guaranteed by design, not subject to production testing.

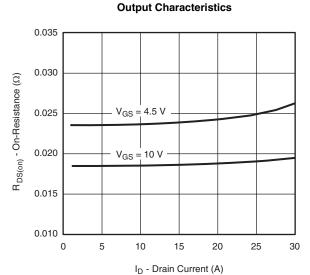
Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.



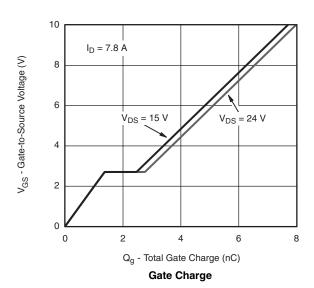
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TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted



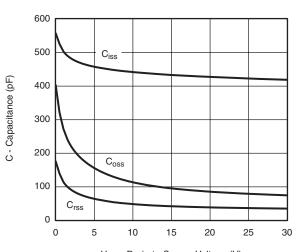


On-Resistance vs. Drain Current

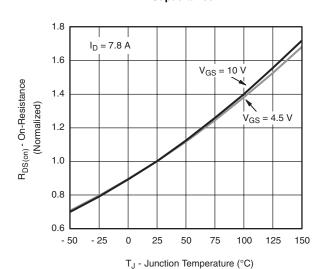


10 8 I_D - Drain Current (A) 6 2 T_C = 125 °C - 55 °C 0.5 1.0 2.5 0.0 1.5 3.0

V_{GS} - Gate-to-Source Voltage (V) **Transfer Characteristics**



V_{DS} - Drain-to-Source Voltage (V) Capacitance



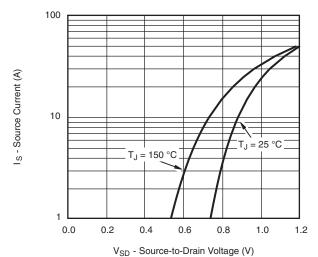
On-Resistance vs. Junction Temperature

Si4128DY

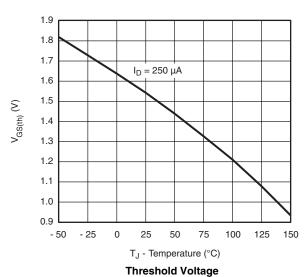
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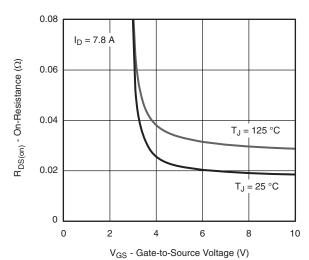
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TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted

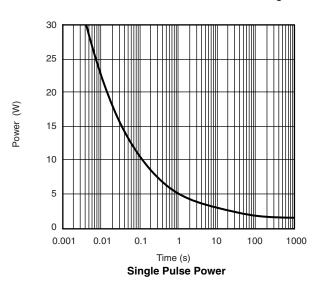


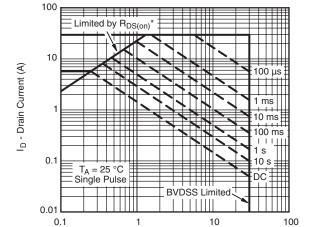
Source-Drain Diode Forward Voltage





On-Resistance vs. Gate-to-Source Voltage





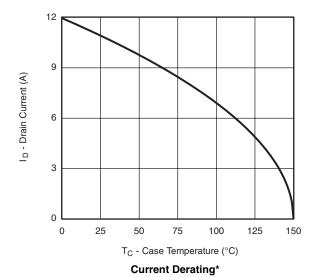
 V_{DS} - Drain-to-Source Voltage (V) * V_{GS} > minimum V_{GS} at which $R_{DS(on)}$ is specified

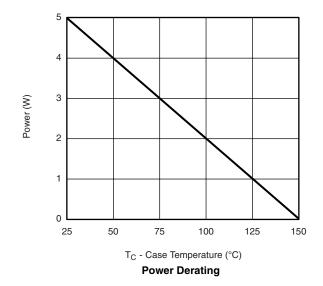
Safe Operating Area, Junction-to-Ambient



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TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted





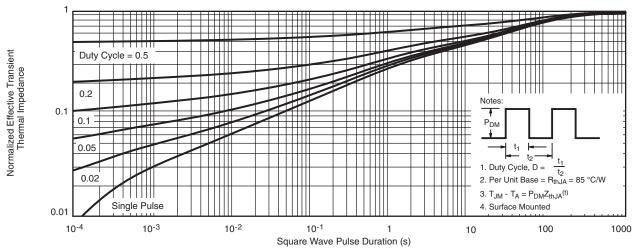
^{*} The power dissipation P_D is based on $T_{J(max)} = 150$ °C, using junction-to-case thermal resistance, and is more useful in settling the upper dissipation limit for cases where additional heatsinking is used. It is used to determine the current rating, when this rating falls below the package limit.

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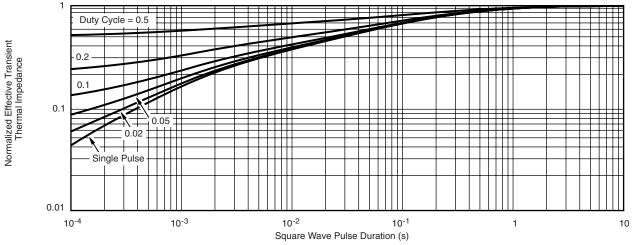
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TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted



Normalized Thermal Transient Impedance, Junction-to-Ambient



Normalized Thermal Transient Impedance, Junction-to-Foot

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